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APPLICATION FOR LETTERS PATENT

Apparatus and Method for Generating a Skip Signal

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1 **RELATED APPLICATION**

2 This application is related to a copending application Serial No.
3 09/169,372, entitled "Method and Apparatus for Fail-Safe Resynchronization with
4 Minimum Latency", filed on October 9, 1998, the disclosure of which is
5 incorporated by reference herein.

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7 **TECHNICAL FIELD**

8 The present invention relates to clock circuitry and, more particularly, to
9 methods and circuits that generate a skip signal using clocks with adjustable
10 timing relationships to one another.

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12 **BACKGROUND**

13 Clock signals are used in electrical circuits to control the flow of data on
14 data communication busses and control the timing and processing of various
15 functions. In particular systems, data is written to a data bus or read from the data
16 bus based on the state of one or more clock signals. These clock signals are
17 necessary to prevent "collision" of data, i.e., the simultaneous transmission of data
18 by two different devices on the same data bus. The clock signals also ensure that
19 the desired data is available on the data bus when read by a device.

20 To transmit data on a bus at high speed and with low latency, a
21 synchronous transmission system is often used. Fig. 1 illustrates a particular
22 example of a data storage system 100 that utilizes a synchronous transmission
23 system. A memory controller 102 controls the writing and reading of data to and
24 from one or more memory storage modules 104, 106, and 108. Memory storage
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modules 104, 106, and 108 may contain any number of memory storage devices, such as random access memories (RAMs). The memory controller 102 and memory storage modules 104-108 are coupled to a data bus 110 and a clock signal transmitted on a pair of lines 112a and 112b. The clock signal may be single-ended or differential. The data bus 110 communicates data between the memory storage modules 104-108 and the memory controller 102. Lines 112a and 112b transmit a clock signal generated by a clock generator 120, coupled to line 112a. Line 112a is "looped back" to line 112b as it passes through memory controller 102. The clock signal carried by line 112a may be referred to as CTM (clock to master or clock to memory controller) and the clock signal carried by line 112b may be referred to as CFM (clock from master or clock from memory controller). Line 112b and each of the lines in data bus 110 are terminated through a resistor 114, which is coupled to Vcc.

The CTM clock signal is sent along with the data signal along bus 110 until it reaches the appropriate memory device, where the clock signal is used to clock the data. By sending the clock signal along with the data signal, the propagation delay of the two signals is matched.

The CTM and CFM clock signals have the same frequency, but have an arbitrary phase relationship. The phase relationship between the two clock signals depends on the physical location of the memory storage module relative to the memory controller. The uncertain phase relationship between the two clock signals creates a non-deterministic setup and hold window for the data from the receive clock domain into the transmit clock domain, which may result in synchronization failures.

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1 An existing skip circuit monitors the timing relationship between the CTM
2 and CFM clocks and determines whether a load pulse signal, which loads the data
3 from the receive clock domain into the transmit clock domain and is generated in
4 the receive clock domain, should be sampled on the rising edge or the falling edge
5 of a quadrature CTM clock. This existing skip circuit works with systems in
6 which the transmit and receive clocks are fixed (i.e., not adjustable). Such a skip
7 circuit is described in copending application Serial No. 09/169,372, incorporated
8 by reference above.

9 The phase difference between the two clocks can be viewed as a fraction of
10 the clock cycle time. This phase difference is defined as t_{TR} . With two clocks of
11 cycle time t_{CYCLE} and with clock phase relative to the source defined as t_{TXCLK} for
12 the transmit clock and t_{RCLK} for the receive clock, t_{TR} is the relative phase between
13 the falling edges of the clocks as a fraction of the clock cycle time. t_{TR} is
14 represented as:

$$t_{TR} = \frac{t_{RCLK} - t_{TXCLK}}{t_{CYCLE}}$$

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19 Using the above equation, the phase position of two clocks with the same
20 relationship would be $t_{TR} = 0$, and two clocks that are inverted from one another
21 would be $t_{TR} = 0.5$ (i.e., a phase difference of 50%).

22 Fig. 2 is a timing diagram illustrating the CTM clock, the phase difference
23 between the CTM and CFM clocks (i.e., t_{TR}), and the resulting skip signal. As
24 shown in Fig. 2, when t_{TR} is in the range of 0 to 0.5, the skip signal value is zero,

1 indicating that the load pulse should be sampled on the rising edge of the CTM
2 clock. When t_{TR} is in the range of 0.5 to 1.0, the skip signal value is one,
3 indicating that the load pulse should be sampled on the falling edge of the CTM
4 clock.

5 The system discussed above utilizes transmit and receive clocks that have
6 fixed timing relationships to one another. Other systems provide adjustable
7 transmit and receive clocks that can be calibrated such that the data can be
8 sampled in the middle of a data window, thereby maximizing the setup and hold
9 window of the receivers. This configuration improves the timing margin of the
10 system. However, the use of calibrated clocks may cause the timing relationship
11 between the transmit clock and the receive clock to deviate from the timing
12 relationship between the CTM and CFM clocks. Thus, the CTM and CFM clocks
13 cannot be used to accurately determine the value of the skip signal in this type of
14 system.

15 An improved architecture described herein addresses these and other
16 problems by generating a skip signal using clocks that have adjustable timing
17 relationships to one another.

18 19 20 **SUMMARY**

21 The improved architecture discussed below generates a skip signal using
22 two clock signals that are individually adjustable. The architecture also maintains
23 backward compatibility with previous architectures that generated a skip signal on
24 the cycle boundary between the CTM clock and the CFM clock.

1 In one embodiment, a clock generator generates a first clock signal and a
2 second clock signal such that the timing relationship between the first and second
3 clock signals is arbitrary. Further, the first and second clock signals are
4 individually adjustable. A phase detector is coupled to receive the first and second
5 clock signals and generate a skip signal by integrating the first clock signal. The
6 skip signal indicates whether the first clock is ahead of the second clock.

7 In another embodiment, the phase detector generates a skip signal by
8 integrating the first clock signal over one half of a clock cycle.

9 In an alternate embodiment, the first and second clock signals are calibrated
10 individually.

11 In a described implementation, the skip signal indicates whether a load
12 pulse should be sampled.

13 In a particular implementation, the skip signal has a first value if the first
14 clock is ahead of the second clock, and the skip signal has a second value if the
15 second clock is ahead of the first clock.
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19 **BRIEF DESCRIPTION OF THE DRAWINGS**

20 Fig. 1 illustrates a particular example of a data storage system.

21 Fig. 2 is a timing diagram illustrating the CTM clock, the phase difference
22 between the CTM and CFM clocks (i.e., t_{TR}), and the resulting skip signal.

23 Fig. 3 is a timing diagram illustrating the timing of various signals in an
24 architecture in which the clock signals are calibrated.
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1 Fig. 4 illustrates a circuit capable of generating a skip signal based on two
2 calibrated clock signals.

3 Fig. 5 is a timing diagram illustrating the relationship between the TCLK
4 and the RCLK signals.

5 Fig. 6 is a flow diagram illustrating a procedure for generating a skip signal
6 using a pair of calibrated clock signals.

DETAILED DESCRIPTION

An improved architecture is discussed herein for generating a skip signal using clocks that have adjustable timing relationships to one another. In particular, the timing of the transmit and the receive clocks are adjustable with respect to each other. This adjustment allows the transmit and receive clocks to be calibrated such that the data can be sampled in the middle of a data window, thereby maximizing the setup and hold window of the receivers. This use of calibrated clocks may cause the timing relationship between the transmit and receive clocks (TCLK and RCLK) to deviate from the timing relationship between the CTM and CFM clocks. Thus, the CTM and CFM clocks cannot be used to generate the skip signal in an architecture having calibrated transmit and receive clocks.

The architecture described herein uses the calibrated transmit and receive clocks to determine the skip signal value. This architecture also maintains backward compatibility for systems that generate the skip circuit signal on the cycle boundaries between the CTM and CFM clocks. Throughout the description of the architecture, the terms “calibrated clocks” and “adjustable clocks” have the same meaning; i.e., two clocks that can have their timing adjusted with respect to one another to produce the desired calibration. Each of the two clocks can be adjusted (or calibrated) individually.

Fig. 3 is a timing diagram illustrating the timing of various signals in an architecture in which the clock signals are calibrated. Specifically, Fig. 3 shows the timing relationship between CTM and the transmit clock (TCLK) and shows the timing relationship between CFM and the receive clock (RCLK). Prior to

calibration, TCLK is 90 degrees behind CTM and RCLK is 180 degrees behind CFM, as illustrated by the solid lines for TCLK and RCLK. Broken lines associated with TCLK represent the effects of calibration. As shown, the TCLK signal can be adjusted forward or backward with respect to CTM to establish the desired calibration. Similarly, broken lines associated with RCLK represent the effects of calibration. As with TCLK, the RCLK signal can be adjusted forward or backward with respect to CFM to produce the desired calibration. The TCLK and RCLK signals can be adjusted (or calibrated) independently of one another.

A dual-loop delay-locked loop (DLL) circuit on, for example, a memory device provides for the adjustment of TCLK and RCLK. The dual-loop DLL includes digitally-controlled mixers such that each mixer can provide a clock signal which can be adjusted up to 360 degrees. Separate mixers are provided for TCLK and RCLK. The control settings for the clock signal adjustment can be handled on the memory device or on the memory controller. In a particular implementation, the control settings for the clock signal adjustment is handled on the memory controller to allow interaction with testing procedures performed by the memory controller.

A broken line associated with TCLK and CTM indicates that the unadjusted TCLK signal is 90 degrees out of phase with CTM. Another broken line associated with TCLK and TXDATA indicates that the adjusted TCLK signal is aligned with the beginning of a corresponding TXDATA window. As shown in Fig. 3, each rising edge and each falling edge of the adjusted TCLK signal is aligned with the beginning of a particular TXDATA window. Thus, TCLK is adjusted such that it is synchronized with TXDATA.

logic '0'). Thus, instead of using external clocks to generate a SKIP signal, the system generates a SKIP signal using the adjusted clocks TCLK and RCLK.

In one embodiment, the quadrature phase detector 252 in Fig. 4 is implemented using an integrator which integrates the data waveform over half a clock cycle. This integration is performed instead of sampling the data at the rising edge of the clock (i.e., the rising edge of TCLK). Integrating the data waveform over half a clock cycle is substantially equivalent to sampling the data 90 degrees later than the rising edge of the clock. Thus, the integration operation accomplishes the 90 degree phase shift of the clock for backward compatibility with non-adjustable clock signals. In this embodiment, RCLK is used to integrate TCLK using the quadrature phase detector 252.

Fig. 5 is a timing diagram illustrating the relationship between the TCLK and the RCLK signals. The data sampling point is shown as the middle of each positive half cycle of the RCLK signal. As shown in Fig. 5, the RCLK signal is slightly behind the TCLK signal (i.e., TCLK is ahead of RCLK). Thus, the inverted output of the quadrature phase detector 252 (Fig. 4) is high (a logic '1'), and the resulting SKIP signal is low (a logic '0').

Fig. 6 is a flow diagram illustrating a procedure 300 for generating a skip signal using a pair of calibrated clock signals. Initially, the procedure 300 receives a transmit clock signal TCLK and a receive clock signal RCLK (block 302). The TCLK signal is shifted by 90 degrees using an integrator that integrates the data waveform (i.e., the TCLK signal) over half of a clock cycle (block 304). After integrating the data waveform, the integrator outputs an inverted skip signal (block 306). Finally, the procedure 300 inverts the output of the integrator to generate the skip signal (block 308). As mentioned above, alternate embodiments may not

1 require the inversion of the skip signal. In such embodiments, block 308 of Fig. 6
2 is not required.

3 Thus, a system has been described that generates a skip signal based on a
4 pair of adjustable clocks that can be calibrated such that the data can be sampled in
5 the middle of a data window. Furthermore, the described system provides
6 backward compatibility that allows for the generation of a skip signal if the pair of
7 clocks are not adjustable (i.e., the clocks have fixed timing with respect to each
8 other).

9 Although the description above uses language that is specific to structural
10 features and/or methodological acts, it is to be understood that the invention
11 defined in the appended claims is not limited to the specific features or acts
12 described. Rather, the specific features and acts are disclosed as exemplary forms
13 of implementing the invention.
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